

_	Application No.	Applicant(s)	
	09/750,200	LIN ET AL.	
	Examiner	Art Unit	
	Paul Dinh	2825	

	SEAR	CHED	
Class	Subclass	Date	Examiner
716	1	8/27/2003	PD
716	4-5	8/27/2003	PD
714	726-729	8/27/2003	PD
714	738-739	8/27/2003	PD
above	update	1/30/2004	PD
	y.		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East search	8/27/2003	PD
East search	1/30/2004	PD
pseudo random pattern on-die on-chip embed weight bit multiplex memory scan	8/27/03 1/30/04	PD